## CoFeB/酸化物界面へのフッ化物と窒化物導入による垂直磁気異方性の変化

## Effects of nitride and fluoride introduction on perpendicular anisotropy at CoFeB/Oxides interfaces

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**1. Introduction:** CoFeB/oxide stack with perpendicular magnetic anisotropy (PMA) is one of the key technologies to realize high performance magnetoresistive random access memory. CoFeB/oxide PMA stacks with high interface anisotropy energy ( $K_{int}$ ) have already been achieved by MgO deposition on CoFeB[1,2], but exploring the materials to induce higher  $K_{int}$  is still an issue. The formation of Fe-O bonds is considered to bring PMA of this stack due to the degeneracy lifting of Fe3d and hybridization of Fe3d and O2p orbitals [3]. Hence PMA enhancement is reasonably expected if we replace oxygen with anions with different electronegativity. In this study we introduce fluoride and nitride to the CoFeB/oxide interface, to investigate the possibility of manipulation of PMA.

**2. Experimental:** After thermal oxidation of Si substrate, Ta (2.9nm)/wedged  $Co_{0.6}Fe_{0.2}B_{0.2}$  (0-2nm)/dielectric layer were sequentially deposited by sputtering. Three kinds of dielectric layers were investigated: (i) AlF<sub>3</sub> (0–0.6nm)/Al<sub>2</sub>O<sub>3</sub> (4nm); (ii) AlN (0–0.5nm)/Al<sub>2</sub>O<sub>3</sub> (4nm); (iii) MgF<sub>2</sub> (0–0.5nm)/MgO (1.5nm)/Al<sub>2</sub>O<sub>3</sub> (4nm). Those stacks were annealed at 250°C or 300°C in N<sub>2</sub> for 10 minutes. Magneto-optical Kerr effect (MOKE) measurements showed the saturation magnetic field H<sub>s</sub> at the different positions on each wedged structure. Saturation magnetization per area M<sub>s</sub>t<sub>eff</sub> (M<sub>s</sub> is saturation magnetization per volume and t<sub>eff</sub> is effective thickness of ferromagnetic layer) at each point was determined by using superconducting quantum interference device (SQUID).

**3. Results and Discussions:** From the result of MOKE and SQUID,  $k_{eff}t_{eff} \approx 1/2 \mu_0 H_s M_s t_{eff}$  of each position d could be determined. Here,  $\mu_0$  is permeability of vacuum,  $k_{eff}$  represent effective magnetic anisotropy energy density of ferromagnetic layer.  $K_{int}$  also could be determined by considering the relationship:  $k_{eff}t_{eff} = -1/2\mu_0 M_s^2 t_{eff} + K_{int}$  as shown in **fig.1** for typical stacks. From the result shown in **fig.2**, the insertion of both 0.5-nm-thick MgF<sub>2</sub> for the MgO stack and 0.5-nm-thick AlF<sub>3</sub> for the Al<sub>2</sub>O<sub>3</sub> stack brings around 50% increase of  $K_{int}$  in our experimental conditions, while the insertion of AlN at CoFeB/ Al<sub>2</sub>O<sub>3</sub> decrease the  $K_{int}$ . Thus we can surmise that higher electronegativity anion introduction at the CoFeB/Oxides interface is beneficial for the enhancement of  $K_{int}$ , even though the maximum value of  $K_{int}$  achieved in this study was not so high as the reported value for MgO/CoFeB[1]. The physical origin of this observation is not yet fully understood, but we speculate that the transfer of more electrons from ferromagnetic to dielectric by higher electronegativity anion would enhance the PMA of CoFeB/oxide stacks.

[References][1] S. Ikeda, et al., Nature materials 9.9, 721-724 (2010). [2]D. C. Worledge, et al. Appl. Phys. Lett. 98, 022501 (2011). [3] H. X. Yang, et al., Physical Review B 84.5, 054401 (2011).

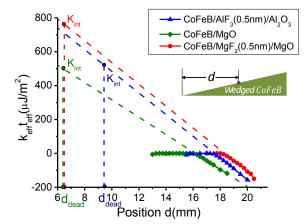


Fig.1  $k_{int}$  values of typical stacks were estimated as the value of  $K_{eff}t_{eff}$  at  $d_{dead}$ , here  $d_{dead}$  is the position that  $t_{eff}$  becomes zero, which determined by SQUID.

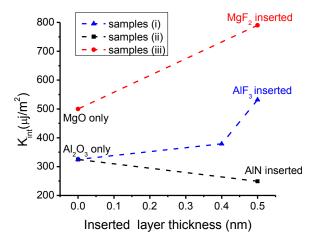


Fig.2 Comparison of  $k_{int}$  of samples (i), (ii), and (iii) with different inserted layer thickness. Annealing temperature of samples (i) and (ii) is optimized as 300°C while samples (ii) annealed at 250°C.